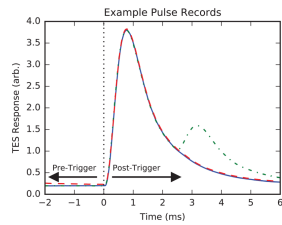


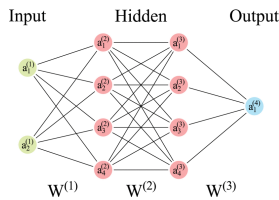
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by Daniel T. Becker, Bradley K. Alpert, Douglas A. Bennett, Mark P. Croce, Joseph W. Fowler, Johnathon D. Gard, Andrew S. Hoover, Young Il Joe, Katrina E. Koehler, John A. B. Mates, Galen C. O'Neil, Michael W. Rabin, Carl D. Reintsema, Daniel R. Schmidt, Daniel S. Swetz, Paul Szypryt, Leila R. Vale, Abigail L. Wessels, and Joel N. Ullom

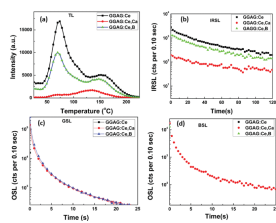
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